

Effect of Silicon Photomultiplier Optical Crosstalk on Detection Performance in Organic Scintillators

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Abstract

1 This paper presents a method to reduce optical crosstalk (OCT) in a MicroFJ30035 silicon photomultiplier (SiPM) by ONSemiconductor, which is a solid-state
2 photon detector capable of detecting single photons. SiPMs are a promising
3 alternative to vacuum photomultiplier tubes in radiation detection scenarios
4 that require low-voltage power requirements, small form factor, and durability.
5 However, the applicability of SiPMs in harsh environments is currently limited
6 due to their temperature-dependent noise, which degrades their signal-to-noise
7 ratio.

8 One of the main sources of noise in SiPMs is OCT, which arises when a photon
9 is produced during an avalanche, and the resulting photon can then trigger
10 another avalanche in neighboring pixels, leading to false counts. Therefore, re-
11 ducing OCT is crucial to enhance the performance of SiPMs in high-temperature
12 environments.

13 In this report, we explore a method to reduce OCT in 3mm x 3mm SiPMs
14 by placing a series of Schott bandpass filters over the sensor of the SiPM. Filters
15 with various spectral characteristics were tested on their abilities to suppress
16 unwanted crosstalk signals while preserving the desired signal. We demonstrate
17 the effectiveness of the filters by measuring the OCT in the SiPM before and
18 after the filter installation and show a significant reduction in the OCT.

20 **1. Background and Motivation**

21 Scintillation detectors are widely used in various fields, including high-energy
22 physics [1], medical imaging [2], and nuclear security [3]. These detectors convert
23 the light emitted by the scintillating material into electrical signals, which are
24 then measured to infer the properties of the incident radiation.

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25 Traditionally, vacuum photomultiplier tubes (PMTs) have been the detec-
26 tors of choice for scintillation-based systems. However, they suffer from several
27 limitations, such as high-voltage power requirements, large size, sensitivity to
28 magnetic fields, and fragility, which can limit their use in certain applications.
29 Silicon photomultipliers (SiPMs) offer a compelling alternative to PMTs, as they
30 have lower-voltage power requirements, a smaller form factor, and are more ro-
31 bust.

32 SiPMs consist of an array of micro-cells, each operated in Geiger-mode,
33 that are sensitive to light. When a photon enters a cell, it produces electron-
34 hole pairs, which trigger an avalanche of charge amplification, resulting in a
35 measurable electrical signal. SiPMs' small size and low power consumption
36 make them attractive for use in portable radiation detectors [4], high-spatial
37 resolution radiation trackers [5], and tomography systems [6].

38 However, SiPMs' noise is temperature-dependent, which can reduce their
39 signal-to-noise ratio and limit their applicability in harsh environments. The
40 main sources of noise in SiPMs are dark counts, optical crosstalk, and after-
41 pulsing. Dark counts are thermally-induced electron-hole pairs that can trigger
42 an avalanche in a micro-cell even in the absence of incident photons. Optical
43 crosstalk occurs when a photon is produced during an avalanche, and the re-
44 sulting photon can then trigger another avalanche in neighboring pixels, leading
45 to false counts. Afterpulsing is the delayed release of charge from a micro-cell
46 due to trapping of charge carriers in the cell's material.

47 To overcome these limitations, several approaches have been proposed, in-
48 cluding temperature control systems [7] and gating techniques [8]. In this paper,
49 we reduce optical crosstalk in a 3mm x 3mm SiPM by using different Schott
50 bandpass filters placed over the sensor of the SiPM. This approach is simple,
51 cost-effective, and does not require any modifications to the SiPM structure. We
52 demonstrate the effectiveness of the method by measuring the optical crosstalk
53 in a MicroFJ30035 SiPM before and after the filter installation and show a
54 significant reduction in the crosstalk.

55 **2. Methods**

56 *2.1. Experimental Methods*

57 We began by characterizing the optical crosstalk (OCT) probability of a
58 MircoFJ30035 SiPM in its unmodified state. The SiPM was placed inside a
59 light-tight vacuum chamber with a modified lid, as shown in Figure 1, which
60 included a flange for power and signal lines to pass through to the SiPM. The
61 chamber was maintained at a vacuum of -0.6 Bar and a temperature of 19°C. To
62 measure the SiPM's output signal, we connected it directly to a MiniCircuits
63 ZFL-1000LN+ low-noise amplifier, which was then connected to a 14-bit 500-
64 MSps DT5730 digitizer by CAEN technologies. All signal data was collected on
65 a computer via USB.

66 We powered the SiPM with 5V of overvoltage and collected signal data for
67 five minutes. However, the triggering frequency was over 1000 kHz, causing



Figure 1: Vacuum chamber used for OCT measurement.

68 a buffer overflow in the digitizer. To solve this issue, we used a Fast Digital
69 Detector Emulator to generate a 10 kHz 50% duty cycle TTL pulse, which
70 triggered the digitizer to acquire signal data for a set acquisition window of 992
71 ns.

72 Before testing the SiPM with bandpass filters to reduce OCT, we removed
73 the inductor and fast output connector. These modifications did not affect the
74 performance of the SiPM, as confirmed by measurements taken before and after
75 the modifications.

76 After placing a Semrock BrightLine Multiphoton FF01-520/70-2 Filter on
77 top of the SiPM sensor, we conducted tests using Schott filters to evaluate
78 their OCT reduction capabilities. The Semrock filter was used to reflect OCT-
79 generated photons back at the sensor, in a manner similar to a scintillator.
80 We tested four bandpass filters (KG2, UG5, BG39, and BG40) with different
81 cutoff regions to assess their OCT reduction capabilities in different wavelength
82 regions. Additionally, we used five longpass filters (N-WG280, OG590, RG695,
83 RG850, and RG1000) with various transmittance regions. A schematic of this
84 setup can be seen in Figure 2. Each bandpass filter was applied to the SiPM

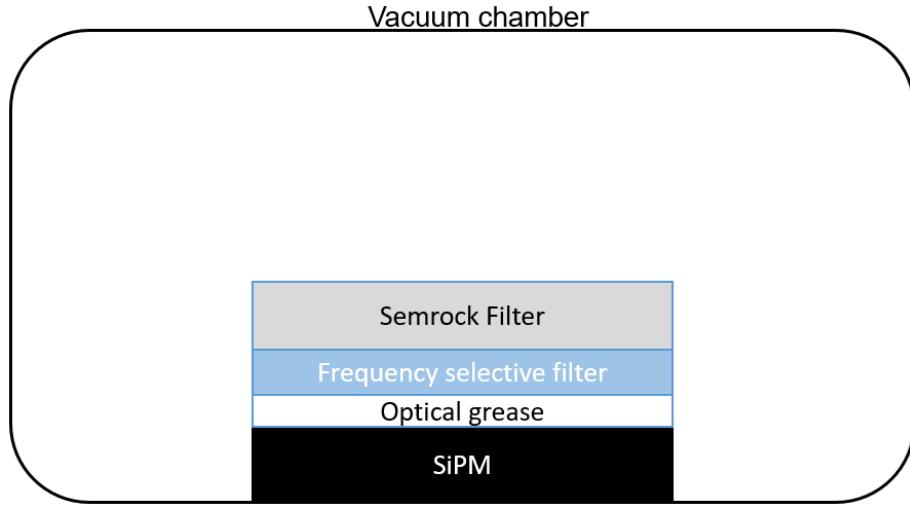


Figure 2: Schematic showing measurement setup.

85 surface using EJ-550 optical grease, which has a refractive index of 1.46.

86 *2.2. Data Processing*

87 We performed a pulse height analysis on the signals from the measurement
 88 acquisition. An example of a raw signal is displayed in Figure 3. The baseline
 89 was calculated as the mean of the first 7 samples. If there was a peak in the first
 90 7 samples of the acquisition window, the window was ignored. The decay of the
 91 pulses was then removed, which improved the calculation of the pulse heights.

92 In each acquisition window, the mean of the six points preceding and includ-
 93 ing the minimum were subtracted from the signal. Then, the resulting trace was
 94 divided by the decay time of the pulse, which was set to 60 ns. Equation 1 rep-
 95 resents this method

$$V_i = V_{Oi} + \frac{1}{\tau} + \sum_{j=1}^{j=i} V_{Oj} \times (t_j - t_{j-1}) \quad (1)$$

96 where $t_{j-1} = 0$ and $V_0 = V - V_{min}$. t is the time in nanoseconds, V is volts in
 97 millivolts, τ is the microcell recharge time of the SiPM, i represents the current
 98 sample, and j represents the previous samples.

99 A bandpass filter was applied to the decay-removed pulse with critical fre-
 100 quencies of 100 MHz and 30 MHz to more easily identify the peak sample. A
 101 peak finding algorithm found all peak samples in the bandpass filtered trace
 102 above a threshold of 2 mV. An example of this method is shown in Figure 4.
 103 The pulse heights were recorded for all acquisition windows for each measure-
 104 ment. The resulting pulse heights were plotted into a histogram as in Figure 5.
 105 The first peak contains all the 1 photoelectron (p.e.) peaks. Single p.e. peaks

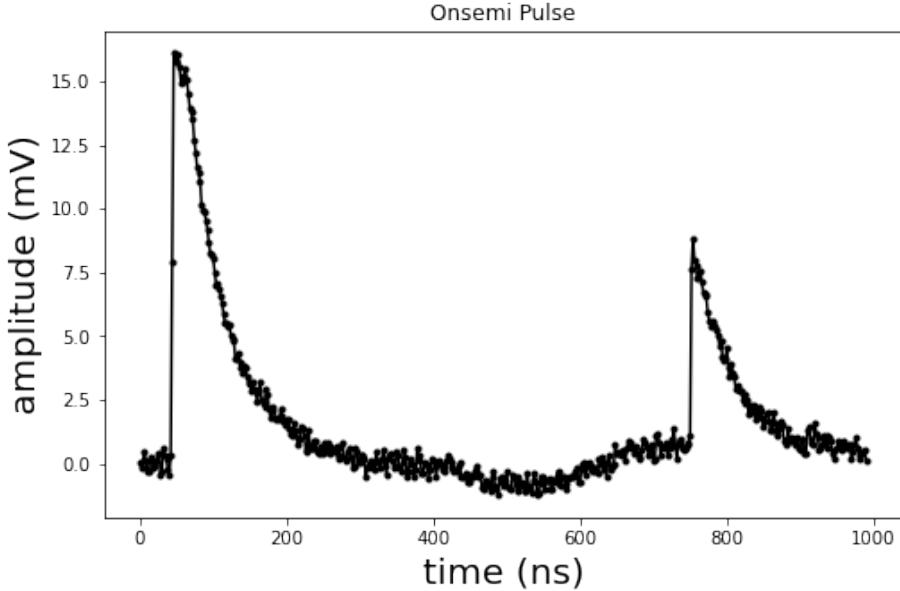


Figure 3: An example of the raw signal in one acquisition window.

106 result from an avalanche from a single microcell. In this case, the avalanches
 107 were caused by dark counts. Beyond the first p.e. peak are higher order p.e.
 108 peaks. These higher order p.e. peaks are caused by prompt OCT. The OCT
 109 photons trigger the surrounding microcells simultaneously to the originally trig-
 110 gered microcell, resulting in peaks with higher amplitude.

111 The dark counts were counted as the area under the 1 p.e. peak in 5 while
 112 the area under the subsequent peaks were counted as OCT events. The OCT
 113 probability was calculated using Equation 2

$$OCT_p = \frac{OCT}{DC + OCT} * 100 \quad (2)$$

114 where OCT_p is the OCT probability, OCT is the number of OCT events, and
 115 DC is the number of dark count events.

116 3. Results

117 The bandpass filters tested reduced optical crosstalk probability in the SiPMs
 118 between 4.8% and 6.1% from the 23.7% measured with the Semrock filter placed
 119 on the sensor to mimick the presence of a detector's surface. The full results
 120 are listed in Table 1.

121 Similarly to [9], the decrease in OCT probability seen in the LPFs suggests
 122 that wavelengths between 600 nm and 1000 nm contribute primarily to OCT.
 123 This is an expected result, as the photons generated during OCT events are

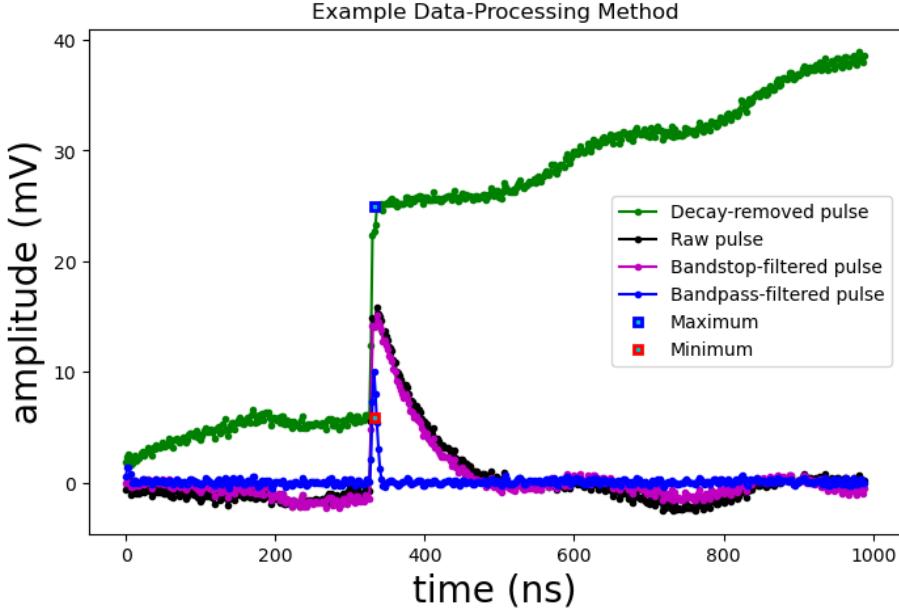


Figure 4: An example of the data-processing method. The calculated maximum is the blue square, and the minimum is the red square.

Table 1: Measured OCT probability for different filters. All measurements following the FF01-520/70-2 include it resting above the longpass and bandpass filters.

Filter Name	OCT Probability	Wavelength Selection
<i>Bare</i>	21.4%	
<i>FF01 – 520/70 – 25</i>	23.7%	Transmittance band: 485nm-555nm
<i>N – WG280</i>	18.7%	200nm-250nm
<i>OG590</i>	18.9%	200nm-550nm
<i>RG695</i>	18.6%	200nm-650nm
<i>RG850</i>	18.1%	200nm-700nm
<i>RG1000</i>	17.8%	200nm-700nm
<i>UG5</i>	17.8%	400nm-600nm
<i>BG39</i>	17.6%	700nm-1000nm
<i>BG40</i>	17.6%	700nm-1000nm
<i>KG2</i>	18.1%	800nm-1200nm

often near infrared wavelength [10]. The BPFs also show significant reduction in OCT probability, with the greatest decreases in the BG39 and BG40. The selection of suitable filters can potentially be a strategy to reduce one of the primary sources of noise in SiPM signals, i.e. OCT, and therefore increase the signal-to-noise ratio.

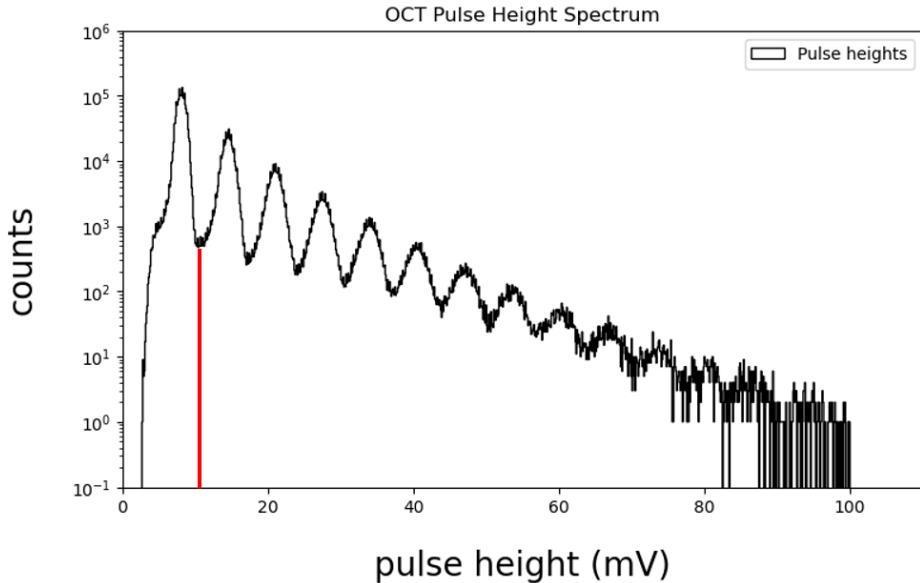


Figure 5: A pulse height spectrum acquired from an OCT measurement. The red line shows the minimum between the 1 and 2 p.e. peaks. All peaks to the left are counted as dark counts while those on the right are considered optical crosstalk.

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